

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10636140	YAMAGISHI, JUNICHI
	<b>Examiner</b>	<b>Art Unit</b>
	Chawan, Sheela C	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	115, 118, 190, 124, 224, 116,	1/18/07	SCC
713	186, 184, 170,	"	"
235	380, 382.5,	"	"
463	25, 29	"	"
340	5.67, 5.53, 5.83, 5.52, 5.8, 5.81, 5.83	"	"
902	3,	"	"
283	904, 77,	"	"
705	1, 26, 42, 67	"	"
702	127	"	"
382	115	6/23/07	SCC
340	5.53	"	"
SEARCH UP- DATE.		"	"

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST, US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB.	1/18/07	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH AND OTHER DATABASES, SEE THE SEARCH HISTORY PRINT OUT AND UP DATE THE SEARCH.	6/23/07	SCC
382/115.CCLS. TEXT SEARCH.	"	"
340/5.53 "	"	"
INTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT. SEARCH IEEE OR INSPEC DATA BASE4.	"	"
ABOVE SEARCH UP-DATE.	"	"

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	115	6/23/07	SCC
340	5.53	"	"